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ISO 9042:2024

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#### ISO 9042:2024(en)

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#### Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see <a href="https://www.iso.org/directives">www.iso.org/directives</a>).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see <a href="https://www.iso.org/iso/foreword.html">www.iso.org/iso/foreword.html</a>.

This document was prepared by Technical Committee ISO/TC 17, *Steel*, Subcommittee SC 7, *Methods of testing* (other than mechanical tests and chemical analysis).

This second edition cancels and replaces the first edition (ISO 9042:1988) which has been technically revised.

The main changes are as follows:

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- clearer definition of t multiplier and corrected values in <u>Table 4</u> (formerly Table 3);
- additional grid examples;
- application to digital images;
- change of terminology: Error % is now  $E_{rel}$ ;
- editorial changes.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at <u>www.iso.org/members.html</u>.

# Steels — Point counting method for statistically estimating the volume fraction of a constituent with a point grid

#### 1 Scope

This document specifies a point counting method for statistically estimating the volume fraction of a constituent through the microstructure of a steel by means of a point grid.

It applies to constituents which are clearly identifiable.

By default, counting is performed manually, but can be computer assisted or substituted by validated computer algorithms.

NOTE In this document, the word "constituent" can designate a phase as well as a micrographic constituent composed of two or more phases.

#### 2 Normative references

There are no normative references in this document.

#### 3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

— ISO Online browsing platform: available at <u>https://www.iso.org/obp</u>

— IEC Electropedia: available at https://www.electropedia.org/ 80f-acf9-2e15ce930a12/iso-9042-2024

#### 4 Symbols and abbreviated terms

The symbols used are given in <u>Table 1</u>.

#### Table 1 — Symbols

Symbols	Definition	Value
n	Number of fields observed	
P <sub>T</sub>	Total number of points in the grid	—
P <sub>i</sub>	Point count on the <i>i</i> <sup>th</sup> field	—
$P_{\mathrm{P}}(i)$	Proportion of grid points in the constituent on the <i>i</i> <sup>th</sup> observed field, expressed as a percentage of the total number of points in the grid.	See <u>Formula (2)</u>
$\overline{P_{\rm P}}$	Arithmetic mean of $P_{\rm P}(i)$	See <u>Formula (3)</u>
Ŝ	Estimate of the standard deviation $\sigma$ of the mean	See <u>Formula (4)</u>
CI	95 % confidence interval	See <u>Formula (5)</u>
$t_{0,05;n-1}$	Student's t-distribution for a two-sided confidence level of 95 % and <i>n</i> observed fields	See <u>Table 4</u> for values

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Symbols	Definition	Value
V <sub>V</sub>	Volume fraction of the constituent expressed as a percentage	See <u>Formula (6)</u>
A <sub>A,est</sub>	Estimated area fraction of the constituent expressed as a percentage	—
E <sub>rel</sub>	Relative error, a measure of the statistical precision, expressed as a percentage; a lower $E_{rel}$ corresponds to a lower error and thus a higher accuracy	See <u>Formula (7)</u>

#### Table 1 (continued)

#### 5 Principle

The basic principle is that a grid with a number of regularly arrayed points, when systematically placed over an image of a micrographic section, can provide, after a representative number of placements on different fields, an unbiased estimation of the volume fraction of the constituent.

The method consists in superimposing the point grid on a given number of fields of the observed surface and in counting the number of points of the grid included in the constituent and then calculating its volume fraction.

#### 6 Apparatus

#### 6.1 Grid

The grid consists of a specified number of regularly spaced and unambiguously defined points. The grids shown in <u>Figures 1</u> to <u>3</u> are given as examples. Alternately, a grid of randomly distributed points may be used.

The grid can be applied via a reticle placed in the eyepiece of the microscope, a graphical overlay on a digital image, the pixel array of a digital image, or other image analysis procedures. It can also be reproduced on a transparency which is placed on the viewing screen of the microscope or on micrographs.





#### Figure 1 — Circular grid